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cont

wherein the optical indicia device comprises a generally planar transparent member having non-transparent optical indicia defining a plurality of transparent regions in the optical indicia device along the optical path, wherein the optical indicia device is mounted in a first plane generally perpendicular to the optical path, and wherein the transparent member is movable with respect to the workpiece between a first position in the first plane, and a second position in a second plane, and wherein the second plane is parallel with the first plane.

13. (Amended) An optical defect inspection system for identifying and locating defects in a workpiece, comprising:

an optical measurement device adapted to view the workpiece along an optical path; and

an optical indicia device located in the optical path, adapted to provide location information with respect to a defect in the workpiece;

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wherein the optical indicia device comprises a generally planar transparent member having non-transparent optical indicia defining a plurality of transparent regions in the optical indicia device along the optical path, wherein the optical indicia device is mounted in a first plane generally perpendicular to the optical path, and wherein the optical indicia device is movable between a first position wherein the optical indicia device is located in the optical path, and a second position wherein the optical indicia device is located outside the optical path.

REMARKS

The Office Action dated November 1, 2002 has been received and carefully reviewed. Claims 8-11, 13, 17-22, 24, and 25 are pending in the application, with claims 1-7, 12, 14-16, and 23 having been cancelled without prejudice or disclaimer and claims 8 and 13 having been amended above. Each of the rejections set forth in the Office Action of November 1, 2002 are addressed in the above amendments and in the following remarks, whereby the pending claims 8-11, 13, 17-22, 24, and 25 are believed